Search Notes

Application/Control No.	Applicant(s)/Patent under Reexamination	
10/651,447	WON ET AL.	
Examiner	Art Unit	
Luan K. Bui	3728	

	SEAR	CHED	
Class	Subclass	Date	Examiner
206	457	8/8/2005	LKB
220	4.21		
	4.22		
	4.23		
	4.24		
	4.25		
	4.29		

INT	INTERFERENCE SEARCHED		
Class	Subclass	Date	Examiner
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SEARCH NOTES (INCLUDING SEARCH STRATEGY)				
	DATE	EXMR		
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